

# **650V GaN Power Transistor (FET)**

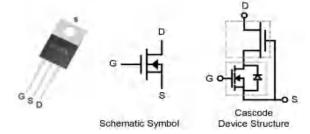
#### **Features**

- Easy to use, compatible with standard gate drivers
- Excellent Q<sub>G</sub> x R<sub>DS(on)</sub> figure of merit (FOM)
- Low  $Q_{RR}$ , no free-wheeling diode required
- Low switching loss
- RoHS compliant and Halogen-free

<b>Product Summary</b>		
$V_{DSS}$	650	V
R <sub>DS(on), typ</sub>	80	mΩ
Q <sub>G, typ</sub>	21	nC
Q <sub>RR, typ</sub>	26	nC

# **Applications**

- High efficiency power supplies
- Telecom and datacom
- Automotive
- Servo motors



# **Packaging**

Part Number	Package	Packaging	Base QTY
RX65T080PS3A	3 Lead TO-220	Tube	50

## Maximum ratings, at T<sub>C</sub>=25 °C, unless otherwise specified

Symbol	Parameter	Limit Value	Unit	
	Continuous drain current @T <sub>C</sub> =25°C		30	Α
I <sub>D</sub>	Continuous drain current @T <sub>C</sub> =100°C		19	Α
	Pulsed drain current @T <sub>C</sub> =25°C (pulse	e width: 10us)	125	Α
I <sub>DM</sub>	Pulsed drain current @T <sub>C</sub> =150°C (pul	se width: 10us)	90	А
V <sub>DSS</sub>	Drain to source voltage (T <sub>J</sub> = -55°C to 150°C)		650	V
V <sub>TDSS</sub>	Transient drain to source voltage <sup>a</sup>		800	V
V <sub>GSS</sub>	Gate to source voltage		±20	V
P <sub>D</sub>	Maximum power dissipation @T <sub>C</sub> =25°C		125	W
T <sub>C</sub>	Otit	Case	-55 to 150	°C
T <sub>J</sub>	Operating temperature	Junction	-55 to 150	°C
T <sub>S</sub>	Storage temperature		-55 to 150	°C
T <sub>CSOLD</sub>	Soldering peak temperature		260	°C

# **RX65T080PS3A**



#### **Thermal Resistance**

Symbol	Parameter	Typical	Unit
Rөлс	Junction-to-case	1	°C/W
Rөла	Junction-to-ambient <sup>b</sup>	50	°C/W

#### Notes:

- a. Off-state spike duty cycle < 0.01, spike duration < 2us
- b. Device on one layer epoxy PCB for drain connection (vertical and without air stream cooling, with 6cm<sup>2</sup> copper area and 70μm thickness)



# Electrical Parameters, at T<sub>J</sub>=25 °C, unless otherwise specified

Symbol	Min	Тур	Max	Unit	Test Conditions
Forward Charac	teristics				
$V_{DSS\text{-MAX}}$	650	-	-	V	V <sub>GS</sub> =0V
$BV_Dss$		1000			V <sub>GS</sub> =0V, I <sub>DSS</sub> =250μA
V <sub>GS(th)</sub>	3	4	5	V	$V_{DS}=V_{GS}$ , $I_D=500\mu A$
<b>5</b> C	-	80	100	mΩ	V <sub>GS</sub> =8V, I <sub>D</sub> =4A, T <sub>J</sub> =25°C
$R_{DS(on)}$	-	160	-	11132	V <sub>GS</sub> =8V, I <sub>D</sub> =4A, T <sub>J</sub> =150°C
I <sub>DSS</sub>	-	10	30	μΑ	V <sub>DS</sub> =700V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C
אטי	-	50	-	μΑ	V <sub>DS</sub> =700V, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C
I <sub>GSS</sub>	-	-	150	nA	V <sub>GS</sub> =20V
IGSS	-	-	-150	nA	V <sub>GS</sub> =-20V
C <sub>ISS</sub>	-	650	-	pF	
C <sub>OSS</sub>	-	60	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =400V, f=1MHz
C <sub>RSS</sub>	-	1.5	-	pF	
C <sub>O(er)</sub>	-	90	-	pF	V 0V V 0 400V
C <sub>O(tr)</sub>	-	180	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =0 - 400V
$Q_{G}$	-	21	-		
$Q_{GS}$	-	6.7	-	nC	V <sub>DS</sub> =400V, V <sub>GS</sub> =0 - 12V, I <sub>D</sub> =5.5A
$Q_{GD}$	-	9	-		
$t_{D(on)}$	-	44	-		
$t_R$	-	16	-	ns	$V_{DS}$ =400V, $V_{GS}$ =0 - 12V, $I_{D}$ =3A, $R_{G}$ =30 $\Omega$
$t_{D(off)}$	-	40	-	ns	V <sub>DS</sub> =400V, V <sub>GS</sub> =0 - 12V, I <sub>D</sub> =3A, K <sub>G</sub> =3052
t <sub>F</sub>	-	12	-		
Reverse Charac	teristics				
	-	1.3	-		V <sub>GS</sub> =0V, I <sub>S</sub> =2A, T <sub>J</sub> =25°C
$V_{SD}$	-	1.9	-	V	V <sub>GS</sub> =0V, I <sub>S</sub> =5A, T <sub>J</sub> =25°C
	-	3	-		V <sub>GS</sub> =0V, I <sub>S</sub> =5A, T <sub>J</sub> =150°C
t <sub>RR</sub>	-	16	-	ns	
$Q_{RR}$	-	26	-	nC	$I_S=3A$ , $V_{GS}=0V$ , $d_i/d_t=1000A/us$ , $V_{DD}=400V$

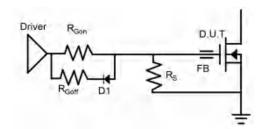
#### Notes:

c. Dynamic on-resistance; see Figure 17 and 18 for test circuit and configurations



#### **Circuit Implementation**

Mostly used in flyback, forward and push-pull converters



### **Recommended Single Ended Drive Circuit**

Recommended gate drive: (0 V, 12 V) with R $_{\rm Gon}$  = 300 - 500  $\Omega$ , R $_{\rm Goff}$  =10  $\Omega$ 

Gate	Gate	Gate	Gate Source	Gate
Ferrite Bead	Resistance	Resistance	Resistance	Diode
(FB)	(R <sub>Gon</sub> )	(R <sub>Goff</sub> )	(R <sub>s</sub> )	(D1)
300 - 600 Ω@100 MHz	300 - 500 $\Omega$	10 Ω	10 kΩ	1N4148



#### Typical Characteristics, at T<sub>C</sub>=25 °C, unless otherwise specified

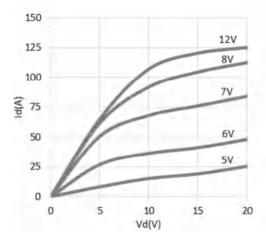


Figure 1. Typical Output Characteristics T<sub>J</sub>=25°C

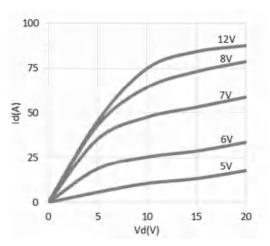


Figure 2. Typical Output Characteristics T<sub>J</sub>=150°C

Parameter: V<sub>GS</sub>

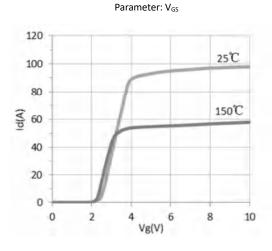


Figure 3. Typical Transfer Characteristics

V<sub>DS</sub>=10V, Parameter: T<sub>J</sub>

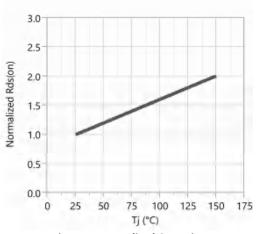


Figure 4. Normalized On-resistance  $I_D=4A$ ,  $V_{GS}=8V$ 

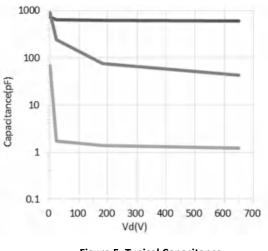


Figure 5. Typical Capacitance  $V_{GS}$ =0V, f=1MHZ

14 12 10 8 8 4 2 0 100 200 300 400 500 600 700 Vd(V)

Figure 6. Typical Coss Stored Energy

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This datasheet is subject to change without notice.



#### Typical Characteristics, at T<sub>C</sub>=25 °C, unless otherwise specified

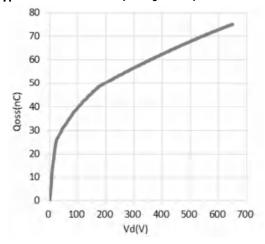


Figure 7. Typical Qoss

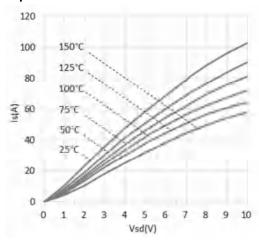


Figure 8. Forward Characteristic of Rev. Diode

Tcase(°C)

Figure 9. Current Derating

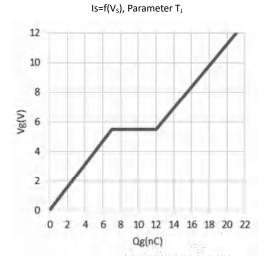


Figure 10. Typical Gate Charge

0 50 100 150 200 Tcase(°C)

Figure 11. Power Dissipation

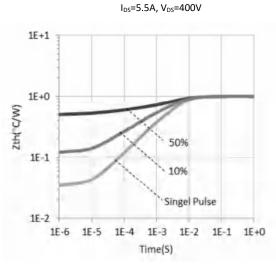
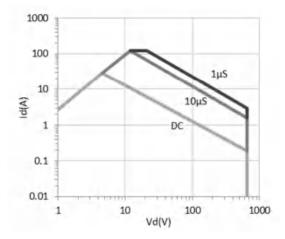


Figure 12. Transient Thermal Resistance



#### Typical Characteristics, at T<sub>C</sub>=25 °C, unless otherwise specified



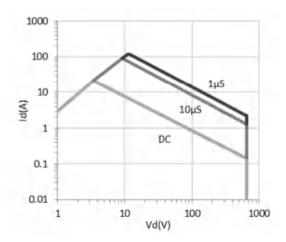


Figure 13. Safe operating Area T<sub>C</sub>=25 °C (calculated based on thermal limits)

Figure 14. Safe operating Area T<sub>C</sub>=80 °C (calculated based on thermal limits)



#### **Test Circuits and Waveforms**

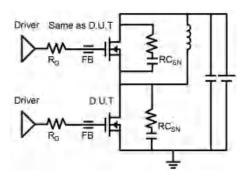


Figure 15. Switching Time Test Circuit

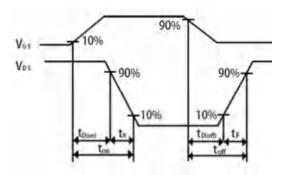


Figure 16. Switching Time Waveform

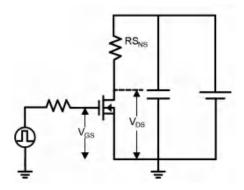


Figure 17. Dynamic  $R_{DS(on)eff}$  Test Circuit

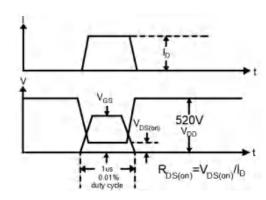


Figure 18. Dynamic  $R_{DS(on)eff}$  Waveform

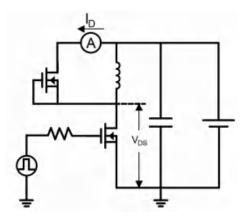


Figure 19. Diode Characteristic Test Circuits

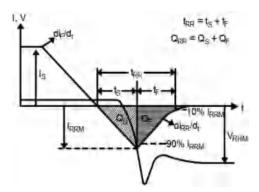


Figure 20. Diode Recovery Waveform



#### **Design Considerations**

Fast switching GaN device can reduce power conversion losses, and thus enable high frequency operations. Certain PCB design rules and instructions, however, need to be followed to take full advantages of fast switching GaN devices.

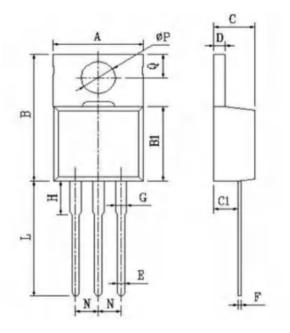
Before evaluating Runxin Micro's GaN devices, please refer to the table below which provides some practical rules that should be followed during the evaluation.

#### When Evaluating Runxin Micro's GaN Devices:

DO	DO NOT
Make sure the traces are as short as possible for both	Using Runxin Micro's devices in GDS board layouts
drive and power loops to minimize parasitic inductance	
Use the test tool with the shortest inductive loop, and	Use differential mode probe or probe ground clip with
make sure test points should be placed close enough	long wires
Minimize the lead length of TO packages when	Use long traces in drive circuit, or long lead length of
installing them to PCB	the devices



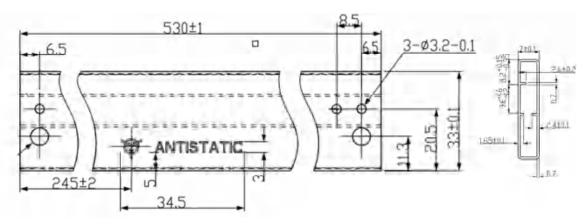
# **Package Outline**



COMMON DIMENSIONS			
CVAADOL	MM		
SYMBOL	MIN	MAX	
Α	10.1	10.5	
В	15.2	15.6	
B1	9.00	9.40	
С	4.40	4.60	
C1	2.40	3.00	
D	1.20	1.40	
Е	0.70	0.90	
F	0.30	0.50	
G	1.17	1.37	
Н	3.30	3.80	
L	13.1	13.7	
N	2.34	2.74	
Q	2.40	3.00	
ФР	3.70	3.90	

#### **Tube Information**

### Dimensions are shown in millimeters



## **Revision History**

Version	Date	Change(s)
0.1	05/30/2023	Release formal datasheet